

<b>Notice of References Cited</b>	Application/Control No. 10/063,934		Applicant(s)/Patent Under Reexamination SATO, TAKAYUKI	
	Examiner Ajay M. Bhatia		Art Unit 2145	Page 1 of 1

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	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Plug & Play IDDQ Monitoring with QTAG, K. Baker et al., 1995, IEEE
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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